

CALL FOR PAPERS



The First International Conference on

Manipulation, Manufacturing and Measurement on the Nanoscale

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29 August – 2 September 2011, Changchun, China

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Sponsors:

National Natural Science Foundation of China Jilin Provincial Science & Technology Department, China Jilin Association for Science and Technology, China Jilin Youth Science and Technology Association, China Changchun University of Science and Technology, China

Topics: Specific topics include, but are not limited to

Nanomanipulation and nanoassembly Nanomaterials and nanocharacterization Nanohandling robots and systems Nanorobotics Nanopositioning systems Nanosensors Nanohandling systems in SEM AFM-based nanohandling Nanofabrication processes and systems Sensor feedback from the nanoscale Control issues in nanohandling Process automation on the nanoscale Micro-to-nano-scale bridging Micro-Nano integration System aspects of nanohandling Modeling of nanoscale effects Nanohandling applications

Down-scaling of manufacturing systems Self-assembly on the nanoscale Error detection in nanomanufacturing Optical nanometrology Nanometrology for MEMS/NEMS Precision lasers for nanometrology Advanced techniques for nanometrology Quantum dots, graphene Nanowires, nanotubes, nanohelices Nanoelectronics and nanomagnetics Nanophotonics and photonic crystals Nanomechanics and nanomechatronics **NEMS** applications Nanopackaging Nanofluidics Nanomedical devices and applications Bio-Nano devices and applications

Workshops: Workshops on selected topics in manipulation, manufacturing and measurement on the nanoscale will be arranged on the first day of the conference. **Workshop attendance is covered by 3M-NANO registration fee.**

Social events: A major goal of the 3M-NANO conference is to support the development of the nanohandling research community and to encourage long-term partnerships and collaborative research activities. The social events and tours will be organized by 3M-NANO free of charge as part of this effort.

Venue: Changchun is the capital city of Jilin Province, located in the northeast of China close to the famous Changbai Mountains. It is a welcoming, modern city with excellent infrastructure and the reputation of being an "automobile and movie city", "city of science and technology" and "granary of north China".

Important Dates

Full paper submission	EXTENDED!!	15 April 2011
Proposals for special sessions (5-6 papers)	EXTENDED!!	15 April 2011
Notification of acceptance		15 May 2011
Final paper submission		15 June 2011
Advanced registration		15 June 2011
Registration for accepted papers		15 June 2011



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